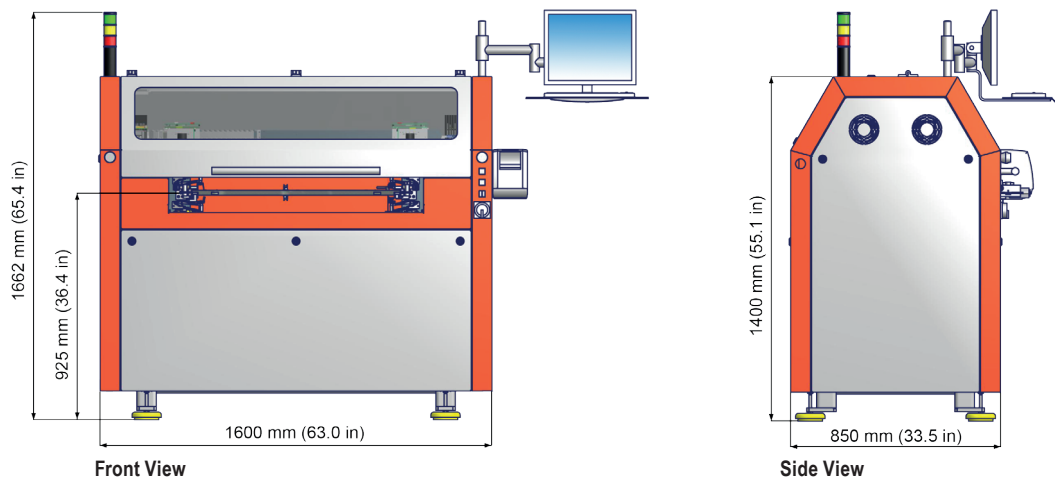


A5 Neo Technical Specifications

Flying Probe Test System



Mechanics

Basic unit with 8 probes (4 top, 4 bottom)
 Universal shuttle system with clamp and stretch mode for testing flexible and rigid boards

Max. board size (X x Y)	640 mm x 495 mm / 25.2" x 19.5"
Min. board size (X x Y)	10 mm x 10 mm / 0.4" x 0.4"
Test area (X x Y)	610 mm x 460 mm / 24.0" x 18.1"
Board thickness	up to 8 mm / 0.32"

Smallest pad	50 μm / 2.0 mil*
Smallest pitch	100 μm / 4.0 mil*
Resolution measurement system	$\pm 2 \mu\text{m}$ / ± 0.08 mil
Repeatable accuracy	$\pm 5 \mu\text{m}$ / ± 0.2 mil

*Soft touch probes	5 g to 15 g
or Standard probes	10 g to 100 g

Electronics

Continuity test	1 Ω to 10 k Ω
Isolation test	up to 25 M Ω (FM) up to 10 G Ω (ohmic) MicroShort Detection®
Test voltage	up to 500 V

Camera System

4 cameras (640 px x 480 px) for fast optical scanning of top and bottom side

Options

- 4-wire measurement with max. 300 mA test current

0.25 m Ω to 1 k Ω	$\pm 2 \%$, min ± 0.025 m Ω
with Kelvin probes	0.2 g to 5 g
Smallest pad	80 μm / 3.2 mil*
Smallest pitch	120 μm / 4.8 mil*

 *with Kelvin probe fine adjustment

- Embedded components test

R 0.5 Ω to 10 M Ω	$\pm 0.5 \%$, min. $\pm 0.5 \Omega$
> 10 M Ω to 50 M Ω	$\pm 2 \%$
C 0.1 pF to 100 μF	$\pm 2 \%$, min. ± 0.03 pF
L 0.2 μH to 5 mH	$\pm 3 \%$, min. $\pm 0.1 \mu\text{H}$

 Diode / Varistor

U_R reverse voltage and	
U_{BR} breakdown voltage	up to 10 V

- LaTest® open detection

with LaTest® probes	1 g to 10 g
High current	1.4 A (1 kHz)

- Enhanced test voltage up to 1000 V
- Retest of fault files from external grid test systems on inquiry
- Repair software with barcode support

Data input format	IPC-D-356A
Network connection	Ethernet, TCP / IP
Power supply	230 V, 50 Hz (115 V, 60 Hz), 900 VA
Temperature	18 $^{\circ}\text{C}$ to 27 $^{\circ}\text{C}$ / 66 $^{\circ}\text{F}$ to 81 $^{\circ}\text{F}$, ± 3 K
Relative humidity	40% to 60%
Machine weight	800 kg / 1763 lbs

All information subject to change without notice!
 September 2013